

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

International Application: PCT/DE99/02380

International Filing Date: 30 July 1999

Inventor: Rau, Wolf-Dieter

For: Method of Measuring the Two-Dimensional
Potential Distribution in CMOS Semiconductors3 / Prel. amdt. A
E. Willis
6-19-0186 Sparks Street
Cambridge MA 02138-2216
12 February 2001Hon.
Assistant Commissioner for Patents
Washington DC 20231Box PCT**Preliminary Amendment Prior to Claims Fee Calculation**

Sir:

With a view to avoiding excess claims fees otherwise due and to rendering his instant application in a condition believed to satisfy formal U.S. prosecution requirements, Applicant courteously requests entry of the instant amendment into the specification and claims of his International Application as amended before the International Preliminary Examination Authority.

In the Specification:

Page 1, line 7: enter --BACKGROUND OF THE INVENTION.

1. Field of the Invention.--;

line 11: insert --2. The Prior Art.--;

N. E. page 2, line 2: insert --OBJECT OF THE INVENTION.--;

N. E. line 8: insert --BRIEF SUMMARY OF THE INVENTION.--;

N. E. page 3, line 13: insert --DESCRIPTION OF THE SINGLE DRAWING.

The drawing schematically depicts the method in accordance with the invention.

DETAILED DESCRIPTION OF THE PREFERRED EMBODIMENT.--;

page 4, line 15: insert --What is claimed is:--;